IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

DAVID R. HEMBREE WARREN M. FARNWORTH SALMAN AKRAM ALAN G. WOOD C. PATRICK DOHERTY ANDREW J. KRIVY

ART UNIT:

EXAMINER:

Division of Serial No. 09/929,388 filed August 14, 2001

Filing Date: February 5, 2002

Title: METHOD FOR TESTING

SEMICONDUCTOR WAFERS (as amended)

Docket No. 96-750.3

TRANSMITTAL LETTER TO THE OFFICIAL DRAFTSPERSON February 5, 2002

BOX PATENT APPLICATION
Assistant Commissioner for Patents
Washington, D.C. 20231

Sir:

Please substitute the attached new formal drawings (six sheets) for the drawings originally filed in parent application serial no. 08/797,719. The new formal drawings have improved line and character quality.

Respectfully submitted:

Stephen A. Graffor Attorney of Record

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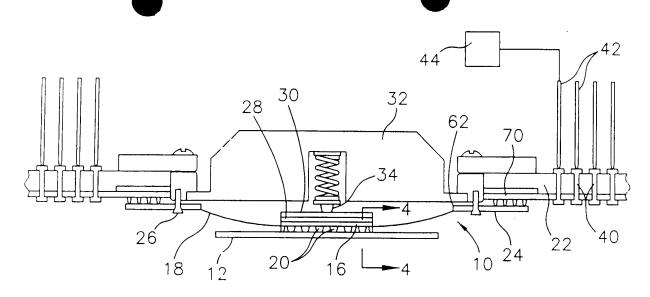


FIGURE 1

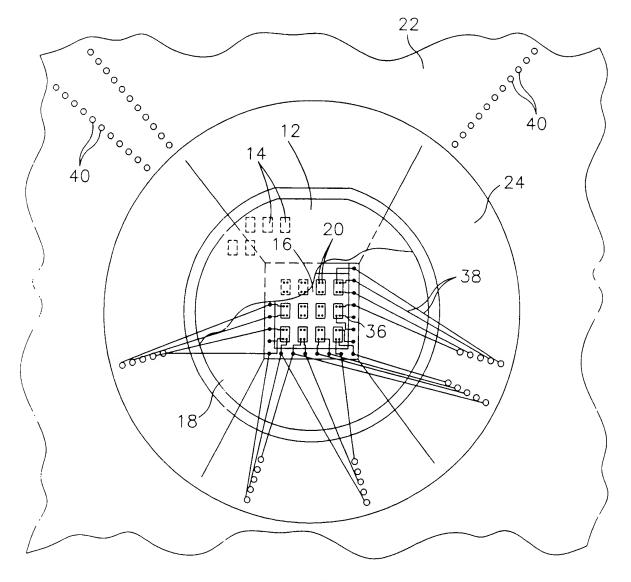
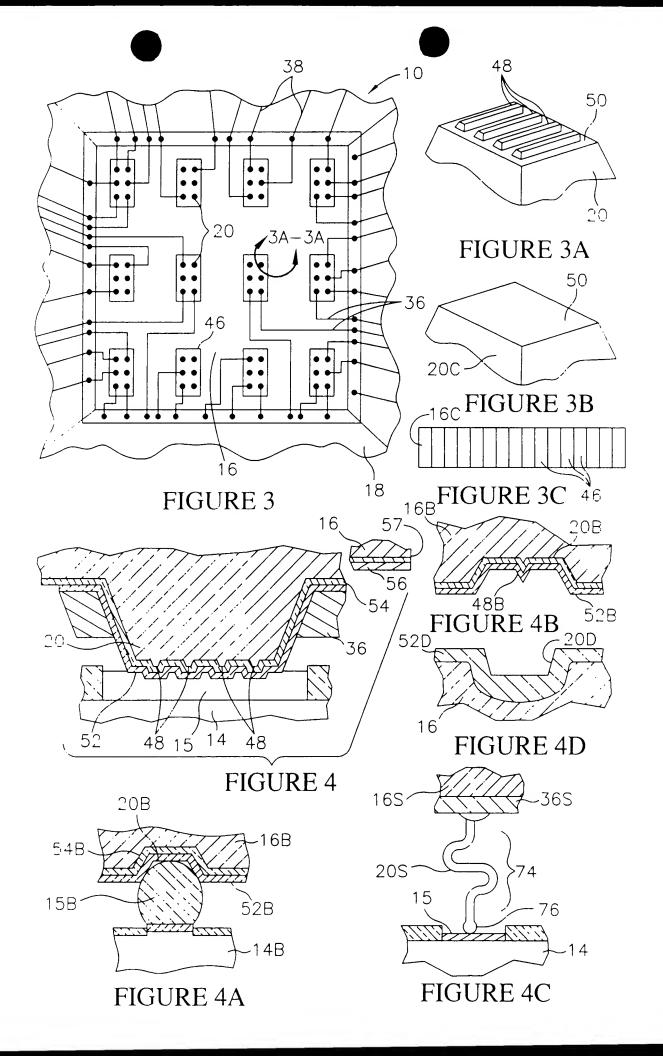
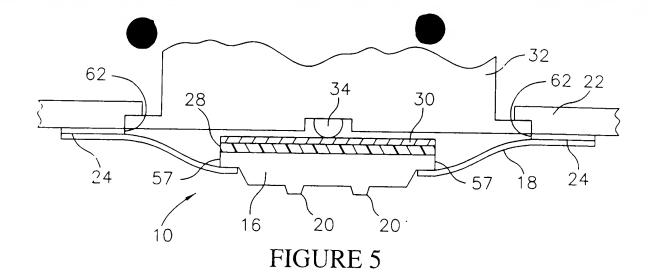
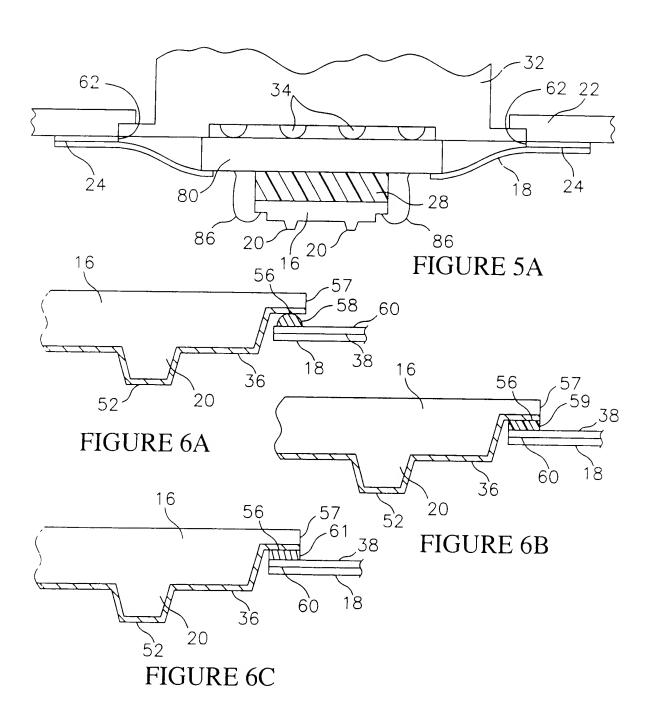
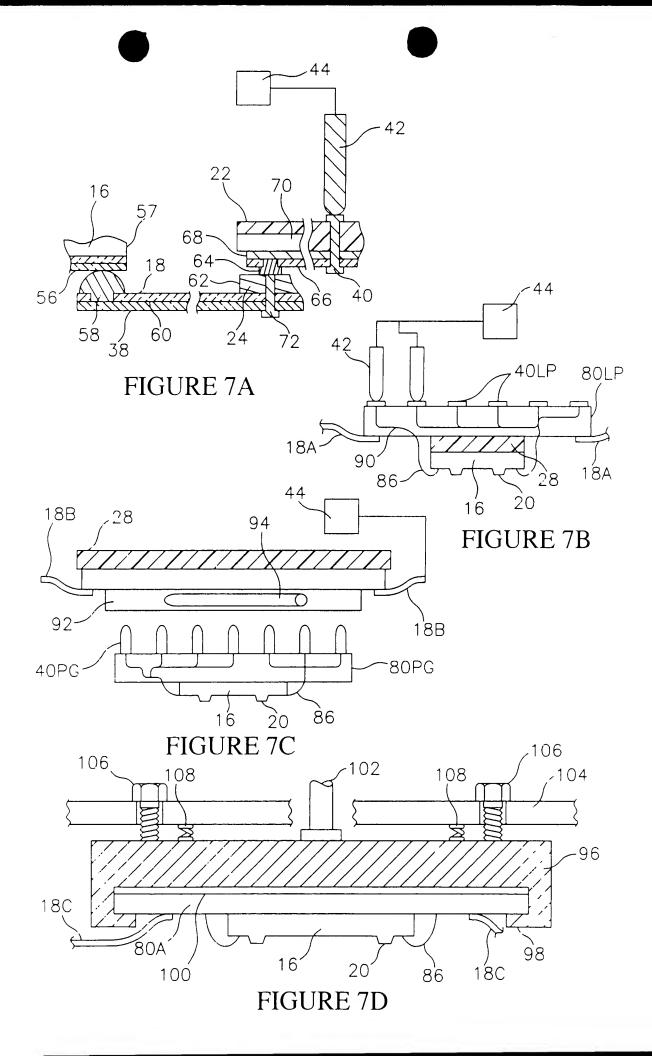


FIGURE 2









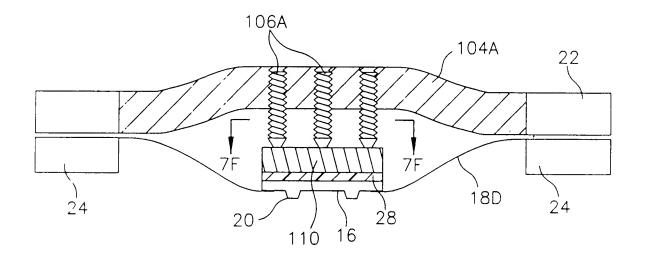


FIGURE 7E

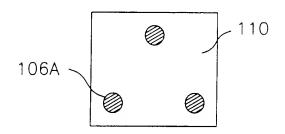


FIGURE 7F

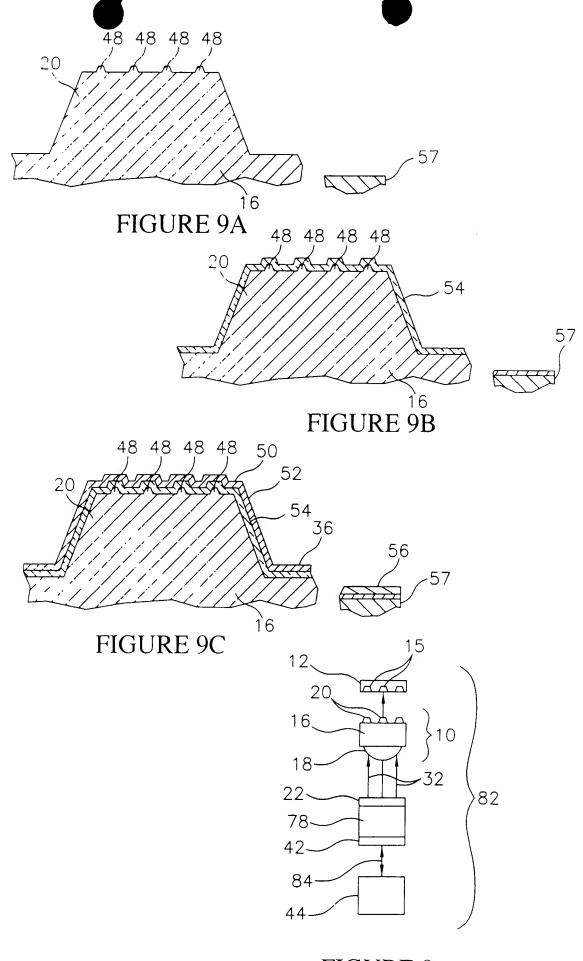


FIGURE 8